ICT Testability In A Perfect World
Or,
In which a lone Test Engineer Dreams Big Dreams

1. Test Points, Test Points, Test Points
   a. Bottom side accessible test pads.
   b. Pad sizes 0.025” or larger.
   c. Test Point to Test Point Centers 0.050” minimum
   d. Multiple Test Points on Power (some) and Ground (many).
   e. Pad size, Test Point Center and Top Access all affect cost.

2. Make My Life Easier With Your Design
   a. Don’t connect that control signal to ground or power, use a resistor.
   b. If there is a choice between JTAG and non-JTAG device, pick JTAG.
   c. If the device has JTAG pins, use them.
   d. If there are multiple JTAG devices, chain them.
   e. Oscillators need disables, don’t let high frequencies out uncontrolled.
   f. Put the Test Points In The CAD as discrete Test Points.
   g. If you have high voltages, make sure I can shut them off during test.

3. You People Are Crazy, I Can’t Do That!
   a. Send us your design and we will evaluate the testability.
      i. Recommend Test Strategy
      ii. Suggest mechanical design for testability improvements.
      iii. Suggest electrical design for testability improvements.
      iv. Commiserate with you.
   b. Call us and we can talk about it.